Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/631,836	KIM, JOON TAE
Examiner	Art Unit

2622

Sherrie Hsia

	SEAR	CHED	
Class	Subclass	Date	Examiner
348	614, 607, 624, 914	4/06	SM
375	229, 232,		
	286, 346		
	260		
H04N	5/21		
	5/213		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SE/	ARCH NOT SEARCH)
	4 18108	DATE	EXMR
EAST		4/06	sy